

Search Notes

Application/Control No.

10/734,905

Examiner

Sun J. Lin

Applicant(s)/Patent under
Reexamination

HWANG ET AL.

Art Unit

2825

SEARCHED

Class	Subclass	Date	Examiner
716	2	11/11/2005	JSL
716	16	11/11/2005	JSL
716	17	11/11/2005	JSL
716	18	11/11/2005	JSL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST [USPAT;US- PGPUB;EPO;JPO;DERWENT;IBM_T DB]	11/11/2005	JSL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner